

Notice of References Cited

Application/Control No.

10/582,442

Applicant(s)/Patent Under
Reexamination
HEDSTROM, HANSExaminer *QPL* 12/07

Quyen P. Leung

Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,521,840	02-2003	Kreutz, Tomas	174/151
*	B	US-5,938,152	08-1999	Kreutz, Tomas	248/56
*	C	US-6,543,780	04-2003	Kogler et al.	277/312
*	D	US-2005/0121217	06-2005	Hedstrom, Hans Irar	174/052.3
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2003052895 A1	06-2003	World Intellect	HEDSTROM et al.	
	O	GB 2204922 A	11-1988	United Kingdom	TWIST, MICHAEL	
	P	DE 20116654 U1	03-2002	Germany	ROXTEC INGENIEUR	
	Q	JP 2001136645 A	05-2001	Japan	IGARASHI et al.	
	R	DE 29924396 U1	01-2003	Germany	HEIMPEL et al.	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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